Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	(simultaneou$4 same (shrink$4 or shrunk$4 or (scal$4 adj down) or (down adj siz$4)) same (circuit near layout))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/20 11:22
L2	0	((asymmetric$4 or (non-uniform$4)) same (shrink$4 or shrunk$4 or (scal$4 adj down) or (down adj siz$4)) same (circuit near layout))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/20 11:24
L3	20	((asymmetric$4 or (non-uniform$4)) same (shrink$4 or shrunk$4 or (scal$4 adj down) or (down adj siz$4))) and (circuit same layout)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/20 11:25
L4	1	((asymmetric$4 or (non-uniform$4)) same (scal$4 adj factor$2) same (shrink$4 or shrunk$4 or (scal$4 adj down) or (down adj siz$4))) and (circuit same layout)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/20 11:26
S1	1662	716/2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:28
S2	992	716/11	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:23
S3	1	(716/2).ccls. and (shrink$4 or shrunk$4) same (asymmetric$5 or non-uniform) and (fabrication adj process)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:31
S4	0	(716/11).ccls. and (shrink$4 or shrunk$4) same (asymmetric$5 or non-uniform) and (fabrication adj process)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:31
S5	1	("716"/$).ccls. and (shrink$4 or shrunk$4) same (asymmetric$5 or non-uniform) and (fabrication adj process)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:31

S6	60	(shrink$4 or shrunk$4) same (asymmetric$5 or non-uniform) and (fabrication adj process)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:32
S7	60	((shrink$4 or shrunk$4) same (asymmetric$5 or non-uniform)) and (fabrication adj process)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:37
S8	1	((shrink$4 or shrunk$4) same (asymmetric$5 or non-uniform)) and (fabrication adj process) and (scal$4 adj factor$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:36
S9	0	(((shrink$4 or shrunk$4) same (asymmetric$5 or non-uniform)) and (fabrication adj process) and (scal$4 adj factor$2)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:34
S10	57	(shrink$4 or shrunk$4) and (fabrication adj process) and (scal$4 adj factor$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:36
S11	1	(shrink$4 or shrunk$4) same (fabrication adj process) same (scal$4 adj factor$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:37
S12	1	((shrink$4 or shrunk$4) same (asymmetric$5 or non-uniform) same (scal$4 adj factor$2)) and (fabrication adj process)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:38
S13	20	((shrink$4 or shrunk$4) and (asymmetric$5 or non-uniform) and (scal$4 adj factor$2)) and (fabrication adj process)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:42
S14	8	((shrink$4 or shrunk$4) and (asymmetric$5 or non-uniform) and (different adj (scal$4 adj factor$2))) and (fabrication adj process)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:44
S15	0	((shrink$4 or shrunk$4) same (asymmetric$5 or non-uniform) same (different adj (scal$4 adj factor$2))) and (fabrication adj process)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:44

S16	0	((shrink$4 or shrunk$4) same (asymmetric$5 or non-uniform) same (different near (scal$4 adj factor$2))) and (fabrication adj process)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:45
S17	0	((shrink$4 or shrunk$4) same (asymmetric$5 or non-uniform) same (different same (scal$4 adj factor$2))) and (fabrication adj process)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:45
S18	0	((simultaneous$4 same (shrink$4 or shrunk$4)) same (asymmetric$5 or non-uniform) same (scal$4 adj factor$2)) and (fabrication adj process)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/01/19 16:46

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